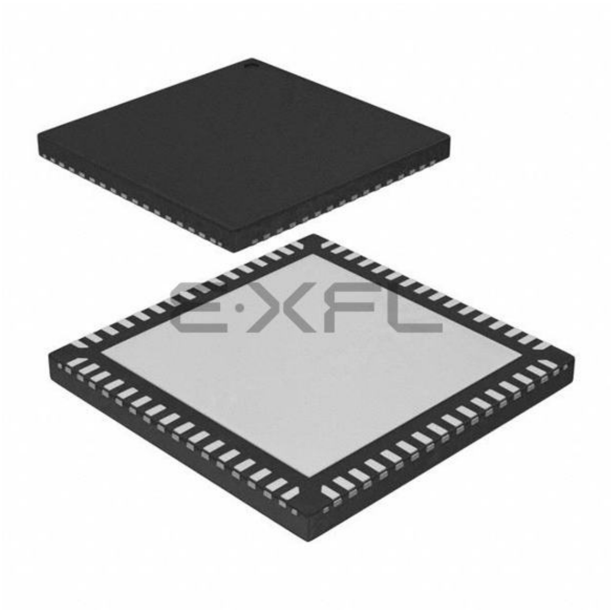


What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Discontinued at Digi-Key
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, I²C, IrDA, LINbus, SmartCard, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, I²S, LCD, POR, PWM, WDT
Number of I/O	53
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.8V
Data Converters	A/D 12bit SAR; D/A 12bit
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TJ)
Mounting Type	Surface Mount
Package / Case	64-VFQFN Exposed Pad
Supplier Device Package	64-QFN (9x9)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm32tg11b540f64im64-ar

3.8.1 Analog Port (APORT)

The Analog Port (APORT) is an analog interconnect matrix allowing access to many analog modules on a flexible selection of pins. Each APORT bus consists of analog switches connected to a common wire. Since many clients can operate differentially, buses are grouped by X/Y pairs.

3.8.2 Analog Comparator (ACMP)

The Analog Comparator is used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. Inputs are selected from among internal references and external pins. The tradeoff between response time and current consumption is configurable by software. Two 6-bit reference dividers allow for a wide range of internally-programmable reference sources. The ACMP can also be used to monitor the supply voltage. An interrupt can be generated when the supply falls below or rises above the programmable threshold.

3.8.3 Analog to Digital Converter (ADC)

The ADC is a Successive Approximation Register (SAR) architecture, with a resolution of up to 12 bits at up to 1 Msps. The output sample resolution is configurable and additional resolution is possible using integrated hardware for averaging over multiple samples. The ADC includes integrated voltage references and an integrated temperature sensor. Inputs are selectable from a wide range of sources, including pins configurable as either single-ended or differential.

3.8.4 Capacitive Sense (CSEN)

The CSEN module is a dedicated Capacitive Sensing block for implementing touch-sensitive user interface elements such a switches and sliders. The CSEN module uses a charge ramping measurement technique, which provides robust sensing even in adverse conditions including radiated noise and moisture. The module can be configured to take measurements on a single port pin or scan through multiple pins and store results to memory through DMA. Several channels can also be shorted together to measure the combined capacitance or implement wake-on-touch from very low energy modes. Hardware includes a digital accumulator and an averaging filter, as well as digital threshold comparators to reduce software overhead.

3.8.5 Digital to Analog Converter (VDAC)

The Digital to Analog Converter (VDAC) can convert a digital value to an analog output voltage. The VDAC is a fully differential, 500 ksps, 12-bit converter. The opamps are used in conjunction with the VDAC, to provide output buffering. One opamp is used per single-ended channel, or two opamps are used to provide differential outputs. The VDAC may be used for a number of different applications such as sensor interfaces or sound output. The VDAC can generate high-resolution analog signals while the MCU is operating at low frequencies and with low total power consumption. Using DMA and a timer, the VDAC can be used to generate waveforms without any CPU intervention. The VDAC is available in all energy modes down to and including EM3.

3.8.6 Operational Amplifiers

The opamps are low power amplifiers with a high degree of flexibility targeting a wide variety of standard opamp application areas, and are available down to EM3. With flexible built-in programming for gain and interconnection they can be configured to support multiple common opamp functions. All pins are also available externally for filter configurations. Each opamp has a rail to rail input and a rail to rail output. They can be used in conjunction with the VDAC module or in stand-alone configurations. The opamps save energy, PCB space, and cost as compared with standalone opamps because they are integrated on-chip.

3.8.7 Liquid Crystal Display Driver (LCD)

The LCD driver is capable of driving a segmented LCD display with up to 8x32 segments. A voltage boost function enables it to provide the LCD display with higher voltage than the supply voltage for the device. A patented charge redistribution driver can reduce the LCD module supply current by up to 40%. In addition, an animation feature can run custom animations on the LCD display without any CPU intervention. The LCD driver can also remain active even in Energy Mode 2 and provides a Frame Counter interrupt that can wake-up the device on a regular basis for updating data.

3.9 Reset Management Unit (RMU)

The RMU is responsible for handling reset of the EFM32TG11. A wide range of reset sources are available, including several power supply monitors, pin reset, software controlled reset, core lockup reset, and watchdog reset.

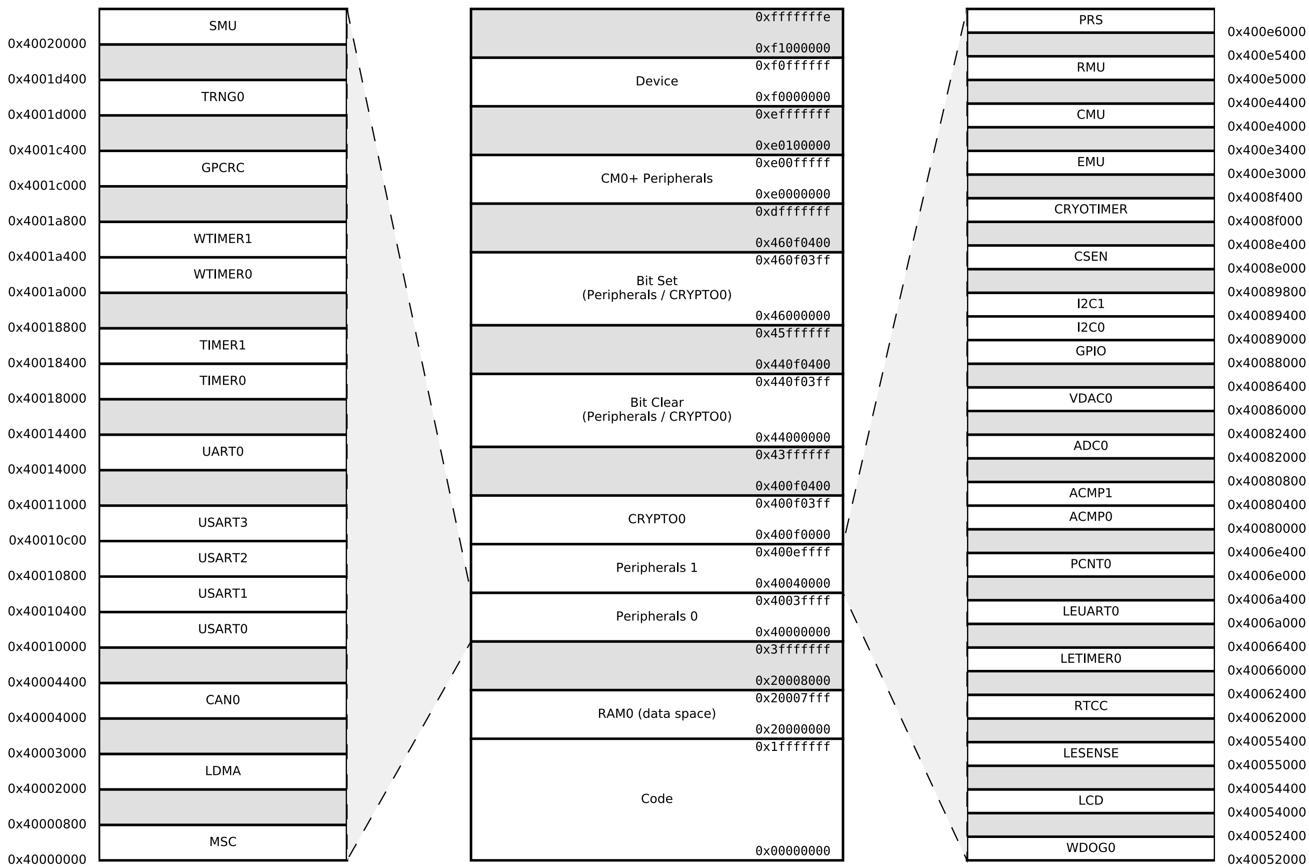


Figure 3.3. EFM32TG11 Memory Map — Peripherals

3.12 Configuration Summary

The features of the EFM32TG11 are a subset of the feature set described in the device reference manual. The table below describes device specific implementation of the features. Remaining modules support full configuration.

Table 3.2. Configuration Summary

Module	Configuration	Pin Connections
USART0	IrDA, SmartCard	US0_TX, US0_RX, US0_CLK, US0_CS
USART1	I^2S, SmartCard	US1_TX, US1_RX, US1_CLK, US1_CS
USART2	IrDA, SmartCard, High-Speed	US2_TX, US2_RX, US2_CLK, US2_CS
USART3	I^2S, SmartCard	US3_TX, US3_RX, US3_CLK, US3_CS
TIMER0	with DTI	TIM0_CC[2:0], TIM0_CDTI[2:0]
TIMER1	-	TIM1_CC[3:0]
WTIMER0	with DTI	WTIM0_CC[2:0], WTIM0_CDTI[2:0]
WTIMER1	-	WTIM1_CC[3:0]

4.1.7 Wake Up Times

Table 4.9. Wake Up Times

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Wake up time from EM1	t_{EM1_WU}		—	3	—	AHB Clocks
Wake up from EM2	t_{EM2_WU}	Code execution from flash	—	10.1	—	μs
		Code execution from RAM	—	3.1	—	μs
Wake up from EM3	t_{EM3_WU}	Code execution from flash	—	10.1	—	μs
		Code execution from RAM	—	3.1	—	μs
Wake up from EM4H[1]	t_{EM4H_WU}	Executing from flash	—	88	—	μs
Wake up from EM4S[1]	t_{EM4S_WU}	Executing from flash	—	282	—	μs
Time from release of reset source to first instruction execution	t_{RESET}	Soft Pin Reset released	—	50	—	μs
		Any other reset released	—	352	—	μs
Power mode scaling time	t_{SCALE}	VSCALE0 to VSCALE2, HFCLK = 19 MHz[4] [2]	—	31.8	—	μs
		VSCALE2 to VSCALE0, HFCLK = 19 MHz[3]	—	4.3	—	μs

Note:

1. Time from wake up request until first instruction is executed. Wakeup results in device reset.
2. VSCALE0 to VSCALE2 voltage change transitions occur at a rate of 10 mV/μs for approximately 20 μs. During this transition, peak currents will be dependent on the value of the DECOUPLE output capacitor, from 35 mA (with a 1 μF capacitor) to 70 mA (with a 2.7 μF capacitor).
3. Scaling down from VSCALE2 to VSCALE0 requires approximately 2.8 μs + 29 HFCLKs.
4. Scaling up from VSCALE0 to VSCALE2 requires approximately 30.3 μs + 28 HFCLKs.

4.1.10 Flash Memory Characteristics[5]

Table 4.17. Flash Memory Characteristics[5]

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Flash erase cycles before failure	EC_{FLASH}		10000	—	—	cycles
Flash data retention	RET_{FLASH}	T ≤ 85 °C	10	—	—	years
		T ≤ 125 °C	10	—	—	years
Word (32-bit) programming time	t_{W_PROG}	Burst write, 128 words, average time per word	20	26	32	µs
		Single word	59	68	83	µs
Page erase time[4]	t_{PERASE}		20	27	35	ms
Mass erase time[1]	t_{MERASE}		20	27	35	ms
Device erase time[2 3]	t_{DERASE}	T ≤ 85 °C	—	54	70	ms
		T ≤ 125 °C	—	54	75	ms
Erase current[6]	I_{ERASE}	Page Erase	—	—	1.7	mA
		Mass or Device Erase	—	—	2.0	mA
Write current[6]	I_{WRITE}		—	—	3.5	mA
Supply voltage during flash erase and write	V_{FLASH}		1.62	—	3.6	V

Note:

1. Mass erase is issued by the CPU and erases all flash.
2. Device erase is issued over the AAP interface and erases all flash, SRAM, the Lock Bit (LB) page, and the User data page Lock Word (ULW).
3. From setting the DEVICEERASE bit in AAP_CMD to 1 until the ERASEBUSY bit in AAP_STATUS is cleared to 0. Internal setup and hold times for flash control signals are included.
4. From setting the ERASEPAGE bit in MSC_WRITECMD to 1 until the BUSY bit in MSC_STATUS is cleared to 0. Internal setup and hold times for flash control signals are included.
5. Flash data retention information is published in the Quarterly Quality and Reliability Report.
6. Measured at 25 °C.

4.1.14 Analog Comparator (ACMP)

Table 4.21. Analog Comparator (ACMP)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input voltage range	V_{ACMPIN}	ACMPVDD = ACMPn_CTRL_PWRSEL [1]	—	—	$V_{ACMPVDD}$	V
Supply voltage	$V_{ACMPVDD}$	BIASPROG[4] ≤ 0x10 or FULL-BIAS[4] = 0	1.8	—	$V_{VREGVDD\_MAX}$	V
		0x10 < BIASPROG[4] ≤ 0x20 and FULLBIAS[4] = 1	2.1	—	$V_{VREGVDD\_MAX}$	V
Active current not including voltage reference[2]	I_{ACMP}	BIASPROG[4] = 1, FULLBIAS[4] = 0	—	50	—	nA
		BIASPROG[4] = 0x10, FULLBIAS[4] = 0	—	306	—	nA
		BIASPROG[4] = 0x02, FULLBIAS[4] = 1	—	6.5	—	µA
		BIASPROG[4] = 0x20, FULLBIAS[4] = 1	—	74	TBD	µA
Current consumption of internal voltage reference[2]	$I_{ACMPREF}$	VLP selected as input using 2.5 V Reference / 4 (0.625 V)	—	50	—	nA
		VLP selected as input using VDD	—	20	—	nA
		VBDIV selected as input using 1.25 V reference / 1	—	4.1	—	µA
		VADIV selected as input using VDD/1	—	2.4	—	µA

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Hysteresis (V_{CM} = 1.25 V, BIASPROG[4] = 0x10, FULLBIAS[4] = 1)	$V_{ACMPHYST}$	HYSTSEL[5] = HYST0	TBD	0	TBD	mV
		HYSTSEL[5] = HYST1	TBD	18	TBD	mV
		HYSTSEL[5] = HYST2	TBD	33	TBD	mV
		HYSTSEL[5] = HYST3	TBD	46	TBD	mV
		HYSTSEL[5] = HYST4	TBD	57	TBD	mV
		HYSTSEL[5] = HYST5	TBD	68	TBD	mV
		HYSTSEL[5] = HYST6	TBD	79	TBD	mV
		HYSTSEL[5] = HYST7	TBD	90	TBD	mV
		HYSTSEL[5] = HYST8	TBD	0	TBD	mV
		HYSTSEL[5] = HYST9	TBD	-18	TBD	mV
		HYSTSEL[5] = HYST10	TBD	-33	TBD	mV
		HYSTSEL[5] = HYST11	TBD	-45	TBD	mV
		HYSTSEL[5] = HYST12	TBD	-57	TBD	mV
		HYSTSEL[5] = HYST13	TBD	-67	TBD	mV
		HYSTSEL[5] = HYST14	TBD	-78	TBD	mV
		HYSTSEL[5] = HYST15	TBD	-88	TBD	mV
Comparator delay[3]	$t_{ACMPDELAY}$	BIASPROG[4] = 1, FULLBIAS[4] = 0	—	30	—	μs
		BIASPROG[4] = 0x10, FULLBIAS[4] = 0	—	3.7	—	μs
		BIASPROG[4] = 0x02, FULLBIAS[4] = 1	—	360	—	ns
		BIASPROG[4] = 0x20, FULLBIAS[4] = 1	—	35	—	ns
Offset voltage	$V_{ACMPOFFSET}$	BIASPROG[4] =0x10, FULLBIAS[4] = 1	TBD	—	TBD	mV
Reference voltage	$V_{ACMPREF}$	Internal 1.25 V reference	TBD	1.25	TBD	V
		Internal 2.5 V reference	TBD	2.5	TBD	V
Capacitive sense internal resistance	R_{CSRES}	CSRESSEL[6] = 0	—	infinite	—	kΩ
		CSRESSEL[6] = 1	—	15	—	kΩ
		CSRESSEL[6] = 2	—	27	—	kΩ
		CSRESSEL[6] = 3	—	39	—	kΩ
		CSRESSEL[6] = 4	—	51	—	kΩ
		CSRESSEL[6] = 5	—	100	—	kΩ
		CSRESSEL[6] = 6	—	162	—	kΩ
		CSRESSEL[6] = 7	—	235	—	kΩ

4.1.15 Digital to Analog Converter (VDAC)

DRIVESTRENGTH = 2 unless otherwise specified. Primary VDAC output.

Table 4.22. Digital to Analog Converter (VDAC)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output voltage	V_{DACOUT}	Single-Ended	0	—	V_{VREF}	V
		Differential[2]	$-V_{VREF}$	—	V_{VREF}	V
Current consumption including references (2 channels)[1]	I_{DAC}	500 ksps, 12-bit, DRIVESTRENGTH = 2, REFSEL = 4	—	396	—	µA
		44.1 ksps, 12-bit, DRIVESTRENGTH = 1, REFSEL = 4	—	72	—	µA
		200 Hz refresh rate, 12-bit Sample-Off mode in EM2, DRIVESTRENGTH = 2, BGRREQTIME = 1, EM2REFENTIME = 9, REFSEL = 4, SETTLETIME = 0x0A, WARMUPTIME = 0x02	—	2	—	µA
Current from HFPERCLK[4]	I_{DAC_CLK}		—	5.8	—	µA/MHz
Sample rate	SR_{DAC}		—	—	500	ksps
DAC clock frequency	f_{DAC}		—	—	1	MHz
Conversion time	$t_{DACCONV}$	f_{DAC} = 1MHz	2	—	—	µs
Settling time	$t_{DACSETTLE}$	50% fs step settling to 5 LSB	—	2.5	—	µs
Startup time	$t_{DACSTARTUP}$	Enable to 90% fs output, settling to 10 LSB	—	—	12	µs
Output impedance	R_{OUT}	DRIVESTRENGTH = 2, 0.4 V ≤ V_{OUT} ≤ V_{OPA} - 0.4 V, -8 mA < I_{OUT} < 8 mA, Full supply range	—	2	—	Ω
		DRIVESTRENGTH = 0 or 1, 0.4 V ≤ V_{OUT} ≤ V_{OPA} - 0.4 V, -400 µA < I_{OUT} < 400 µA, Full supply range	—	2	—	Ω
		DRIVESTRENGTH = 2, 0.1 V ≤ V_{OUT} ≤ V_{OPA} - 0.1 V, -2 mA < I_{OUT} < 2 mA, Full supply range	—	2	—	Ω
		DRIVESTRENGTH = 0 or 1, 0.1 V ≤ V_{OUT} ≤ V_{OPA} - 0.1 V, -100 µA < I_{OUT} < 100 µA, Full supply range	—	2	—	Ω
Power supply rejection ratio[6]	PSRR	Vout = 50% fs. DC	—	65.5	—	dB

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Open-loop gain	G_{OL}	DRIVESTRENGTH = 3	—	135	—	dB
		DRIVESTRENGTH = 2	—	137	—	dB
		DRIVESTRENGTH = 1	—	121	—	dB
		DRIVESTRENGTH = 0	—	109	—	dB
Loop unit-gain frequency[7]	UGF	DRIVESTRENGTH = 3, Buffer connection	—	3.38	—	MHz
		DRIVESTRENGTH = 2, Buffer connection	—	0.9	—	MHz
		DRIVESTRENGTH = 1, Buffer connection	—	132	—	kHz
		DRIVESTRENGTH = 0, Buffer connection	—	34	—	kHz
		DRIVESTRENGTH = 3, 3x Gain connection	—	2.57	—	MHz
		DRIVESTRENGTH = 2, 3x Gain connection	—	0.71	—	MHz
		DRIVESTRENGTH = 1, 3x Gain connection	—	113	—	kHz
		DRIVESTRENGTH = 0, 3x Gain connection	—	28	—	kHz
Phase margin	PM	DRIVESTRENGTH = 3, Buffer connection	—	67	—	°
		DRIVESTRENGTH = 2, Buffer connection	—	69	—	°
		DRIVESTRENGTH = 1, Buffer connection	—	63	—	°
		DRIVESTRENGTH = 0, Buffer connection	—	68	—	°
Output voltage noise	N_{OUT}	DRIVESTRENGTH = 3, Buffer connection, 10 Hz - 10 MHz	—	146	—	μVrms
		DRIVESTRENGTH = 2, Buffer connection, 10 Hz - 10 MHz	—	163	—	μVrms
		DRIVESTRENGTH = 1, Buffer connection, 10 Hz - 1 MHz	—	170	—	μVrms
		DRIVESTRENGTH = 0, Buffer connection, 10 Hz - 1 MHz	—	176	—	μVrms
		DRIVESTRENGTH = 3, 3x Gain connection, 10 Hz - 10 MHz	—	313	—	μVrms
		DRIVESTRENGTH = 2, 3x Gain connection, 10 Hz - 10 MHz	—	271	—	μVrms
		DRIVESTRENGTH = 1, 3x Gain connection, 10 Hz - 1 MHz	—	247	—	μVrms
		DRIVESTRENGTH = 0, 3x Gain connection, 10 Hz - 1 MHz	—	245	—	μVrms

4.1.19 Pulse Counter (PCNT)

Table 4.26. Pulse Counter (PCNT)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input frequency	F_{IN}	Asynchronous Single and Quadrature Modes	—	—	20	MHz
		Sampled Modes with Debounce filter set to 0.	—	—	8	kHz

4.1.20 Analog Port (APORT)

Table 4.27. Analog Port (APORT)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Supply current[2] [1]	I_{APORT}	Operation in EM0/EM1	—	7	—	μA
		Operation in EM2/EM3	—	915	—	nA

Note:
1. Specified current is for continuous APORT operation. In applications where the APORT is not requested continuously (e.g. periodic ACMP requests from LESENSE in EM2), the average current requirements can be estimated by mutiplying the duty cycle of the requests by the specified continuous current number.
2. Supply current increase that occurs when an analog peripheral requests access to APORT. This current is not included in reported module currents. Additional peripherals requesting access to APORT do not incur further current.

4.1.22 USART SPI

SPI Master Timing

Table 4.31. SPI Master Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
SCLK period [1 3 2]	t_{SCLK}		2 * $t_{HFPERCLK}$	—	—	ns
CS to MOSI [1 3]	t_{CS_MO}		-19.8	—	18.9	ns
SCLK to MOSI [1 3]	t_{SCLK_MO}		-10	—	14.5	ns
MISO setup time [1 3]	t_{SU_MI}	IOVDD = 1.62 V	75	—	—	ns
		IOVDD = 3.0 V	40	—	—	ns
MISO hold time [1 3]	t_{H_MI}		-10	—	—	ns

Note:

1. Applies for both CLKPHA = 0 and CLKPHA = 1 (figure only shows CLKPHA = 0).
2. $t_{HFPERCLK}$ is one period of the selected HFPERCLK.
3. Measurement done with 8 pF output loading at 10% and 90% of V_{DD} (figure shows 50% of V_{DD}).

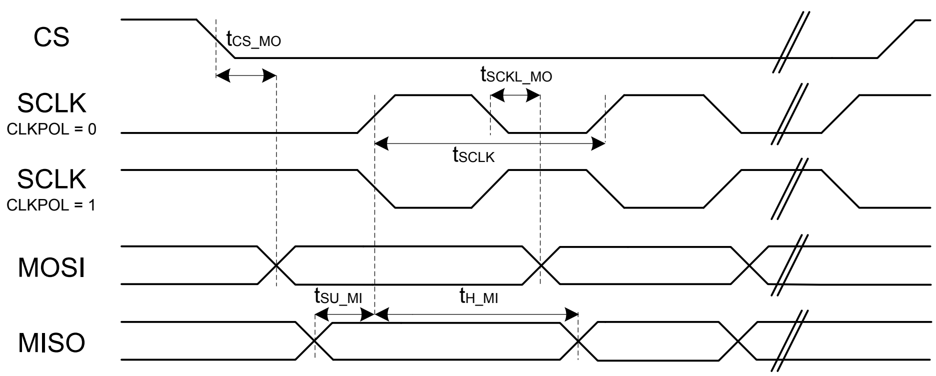


Figure 4.1. SPI Master Timing Diagram

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PE12	76	GPIO	PE13	77	GPIO
PE14	78	GPIO	PE15	79	GPIO
PA15	80	GPIO			

Note:
1. GPIO with 5V tolerance are indicated by (5V).

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PC4	13	GPIO	PC5	14	GPIO
PB7	15	GPIO	PB8	16	GPIO
PA12	17	GPIO	PA13	18	GPIO (5V)
PA14	19	GPIO	RESETn	20	Reset input, active low. To apply an external reset source to this pin, it is required to only drive this pin low during reset, and let the internal pull-up ensure that reset is released.
PB11	21	GPIO	AVDD	23 27	Analog power supply.
PB13	24	GPIO	PB14	25	GPIO
PD0	28	GPIO (5V)	PD1	29	GPIO
PD2	30	GPIO (5V)	PD3	31	GPIO
PD4	32	GPIO	PD5	33	GPIO
PD6	34	GPIO	PD7	35	GPIO
PD8	36	GPIO	PC6	37	GPIO
PC7	38	GPIO	DVDD	39	Digital power supply.
DECOUPLE	40	Decouple output for on-chip voltage regulator. An external decoupling capacitor is required at this pin.	PE4	41	GPIO
PE5	42	GPIO	PE6	43	GPIO
PE7	44	GPIO	PC12	45	GPIO (5V)
PC13	46	GPIO (5V)	PC14	47	GPIO (5V)
PC15	48	GPIO (5V)	PF0	49	GPIO (5V)
PF1	50	GPIO (5V)	PF2	51	GPIO
PF3	52	GPIO	PF4	53	GPIO
PF5	54	GPIO	PE8	57	GPIO
PE9	58	GPIO	PE10	59	GPIO
PE11	60	GPIO	PE12	61	GPIO
PE13	62	GPIO	PE14	63	GPIO
PE15	64	GPIO			

Note:

1. GPIO with 5V tolerance are indicated by (5V).

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PB6	12	GPIO	PC4	13	GPIO
PC5	14	GPIO	PB7	15	GPIO
PB8	16	GPIO	PA12	17	GPIO
PA13	18	GPIO (5V)	PA14	19	GPIO
RESETn	20	Reset input, active low. To apply an external reset source to this pin, it is required to only drive this pin low during reset, and let the internal pull-up ensure that reset is released.	PB11	21	GPIO
PB12	22	GPIO	AVDD	23 27	Analog power supply.
PB13	24	GPIO	PB14	25	GPIO
PD0	28	GPIO (5V)	PD1	29	GPIO
PD2	30	GPIO (5V)	PD3	31	GPIO
PD4	32	GPIO	PD5	33	GPIO
PD6	34	GPIO	PD7	35	GPIO
PD8	36	GPIO	PC6	37	GPIO
PC7	38	GPIO	DVDD	39	Digital power supply.
DECOUPLE	40	Decouple output for on-chip voltage regulator. An external decoupling capacitor is required at this pin.	PE4	41	GPIO
PE5	42	GPIO	PE6	43	GPIO
PE7	44	GPIO	PC12	45	GPIO (5V)
PC13	46	GPIO (5V)	PC14	47	GPIO (5V)
PC15	48	GPIO (5V)	PF0	49	GPIO (5V)
PF1	50	GPIO (5V)	PF2	51	GPIO
PF3	52	GPIO	PF4	53	GPIO
PF5	54	GPIO	PE8	56	GPIO
PE9	57	GPIO	PE10	58	GPIO
PE11	59	GPIO	PE12	60	GPIO
PE13	61	GPIO	PE14	62	GPIO
PE15	63	GPIO	PA15	64	GPIO

Note:

1. GPIO with 5V tolerance are indicated by (5V).

5.10 EFM32TG11B3xx in QFP48 Device Pinout

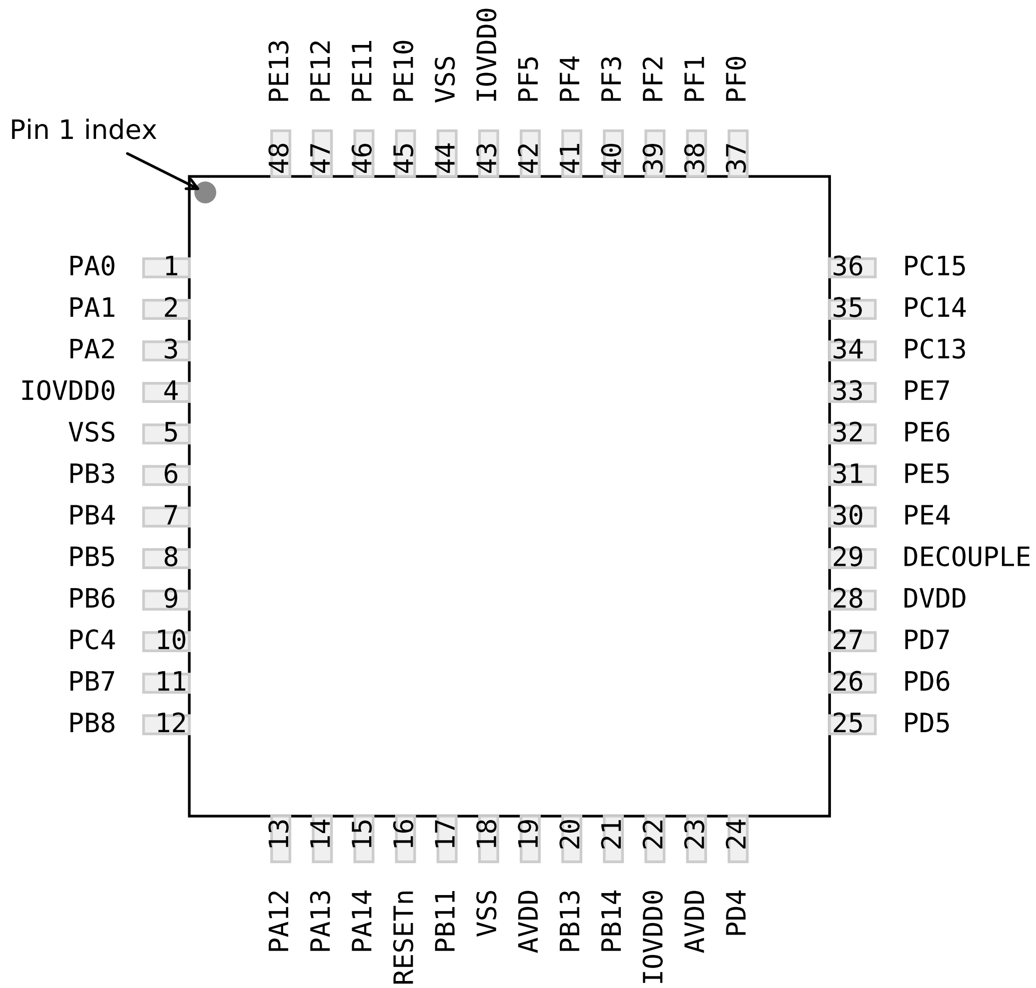


Figure 5.10. EFM32TG11B3xx in QFP48 Device Pinout

The following table provides package pin connections and general descriptions of pin functionality. For detailed information on the supported features for each GPIO pin, see 5.14 GPIO Functionality Table or 5.15 Alternate Functionality Overview.

Table 5.10. EFM32TG11B3xx in QFP48 Device Pinout

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PA0	1	GPIO	PA1	2	GPIO
PA2	3	GPIO	IOVDD0	4 22 43	Digital IO power supply 0.
VSS	5 18 44	Ground	PB3	6	GPIO
PB4	7	GPIO	PB5	8	GPIO
PB6	9	GPIO	PC4	10	GPIO

Port	Bus	CH31	CH30	CH29	CH28	CH27	CH26	CH25	CH24	CH23	CH22	CH21	CH20	CH19	CH18	CH17	CH16	CH15	CH14	CH13	CH12	CH11	CH10	CH9	CH8	CH7	CH6	CH5	CH4	CH3	CH2	CH1	CH0
VDAC0_OUT1 / OPA1_OUT																																	
APORT1Y	BUSAY			PB13		PB11						PB5		PB3				PA15		PA13				PA9				PA5		PA3		PA1	
APORT2Y	BUSBY		PB14		PB12						PB6		PB4						PA14				PA10				PA6		PA4		PA2		PA0
APORT3Y	BUSCY											PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5					
APORT4Y	BUSDY												PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				

6.2 TQFP80 PCB Land Pattern

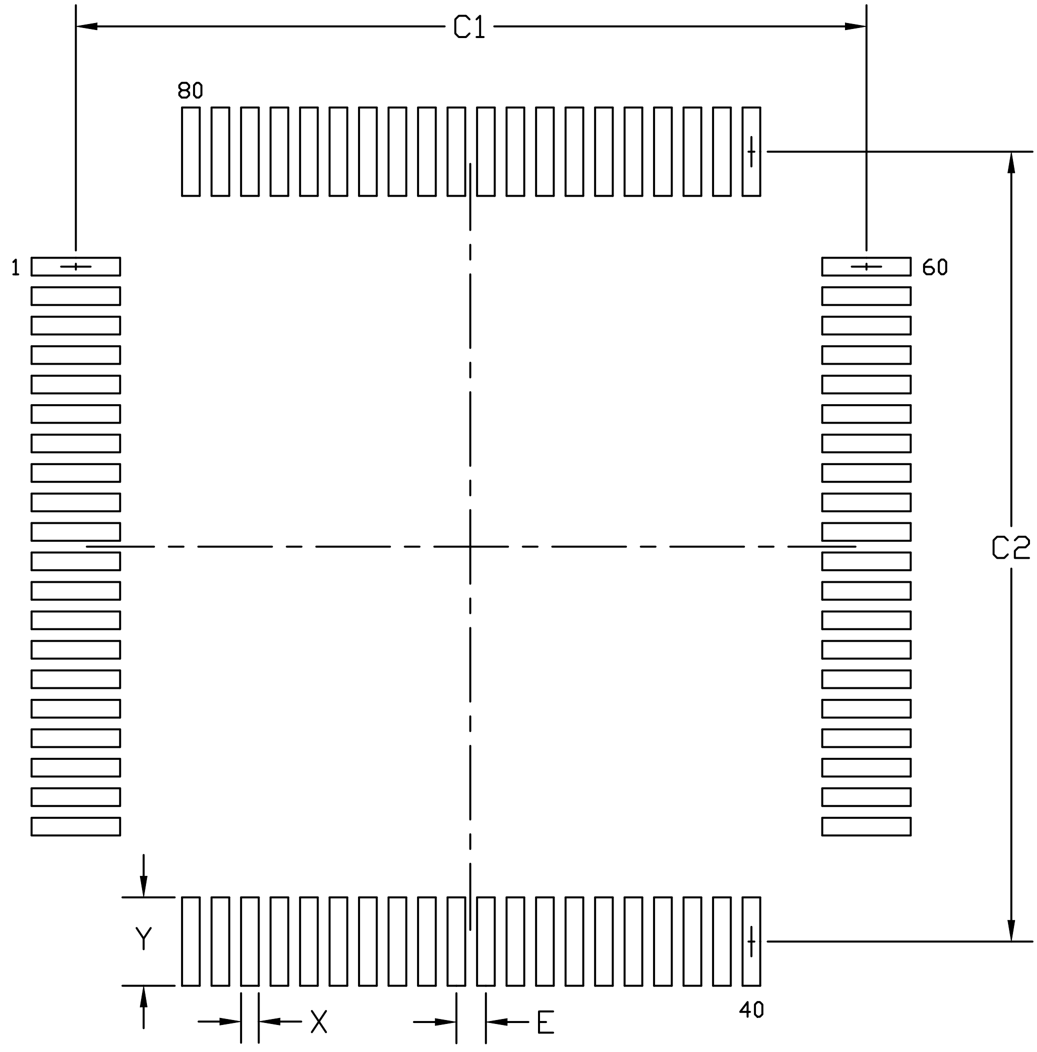


Figure 6.2. TQFP80 PCB Land Pattern Drawing

8.2 TQFP64 PCB Land Pattern

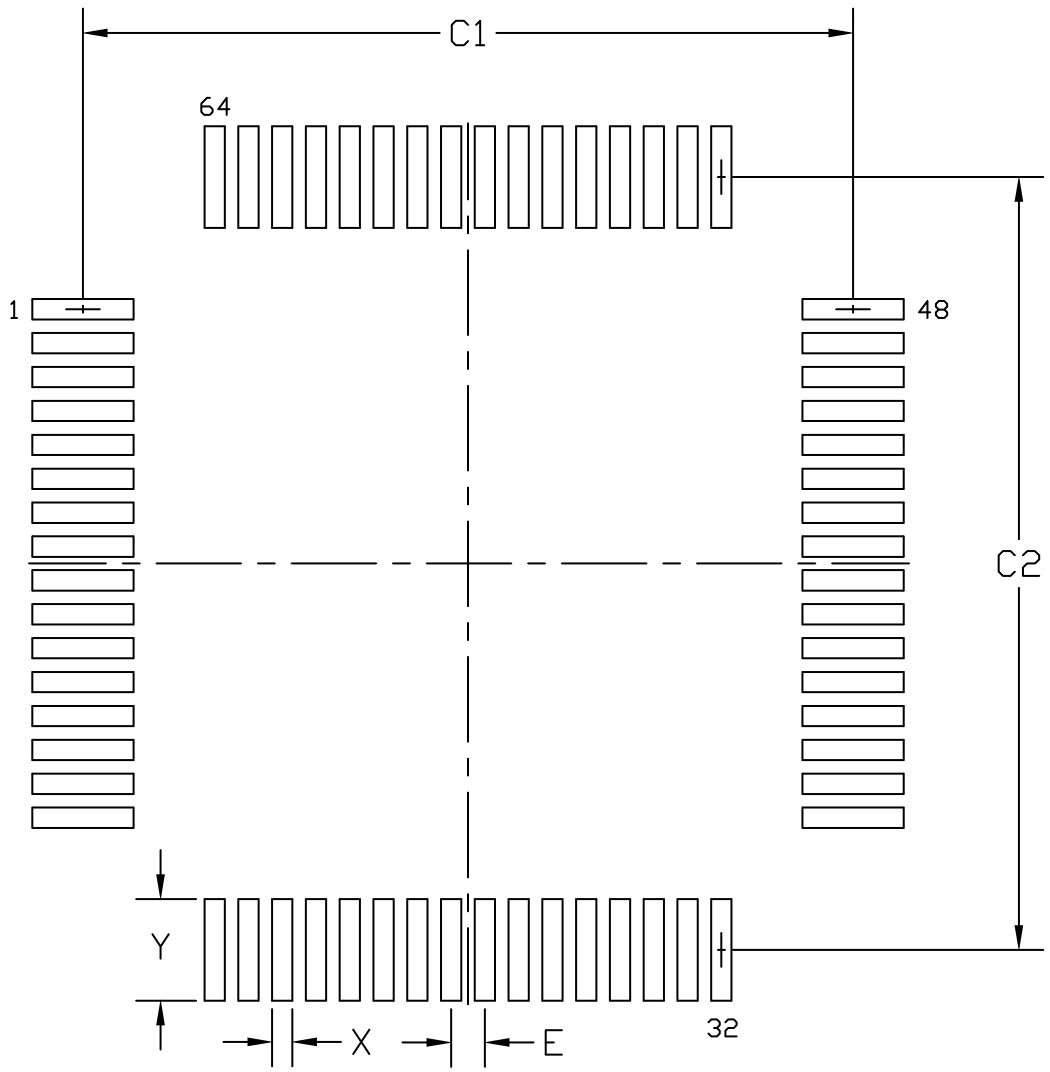


Figure 8.2. TQFP64 PCB Land Pattern Drawing

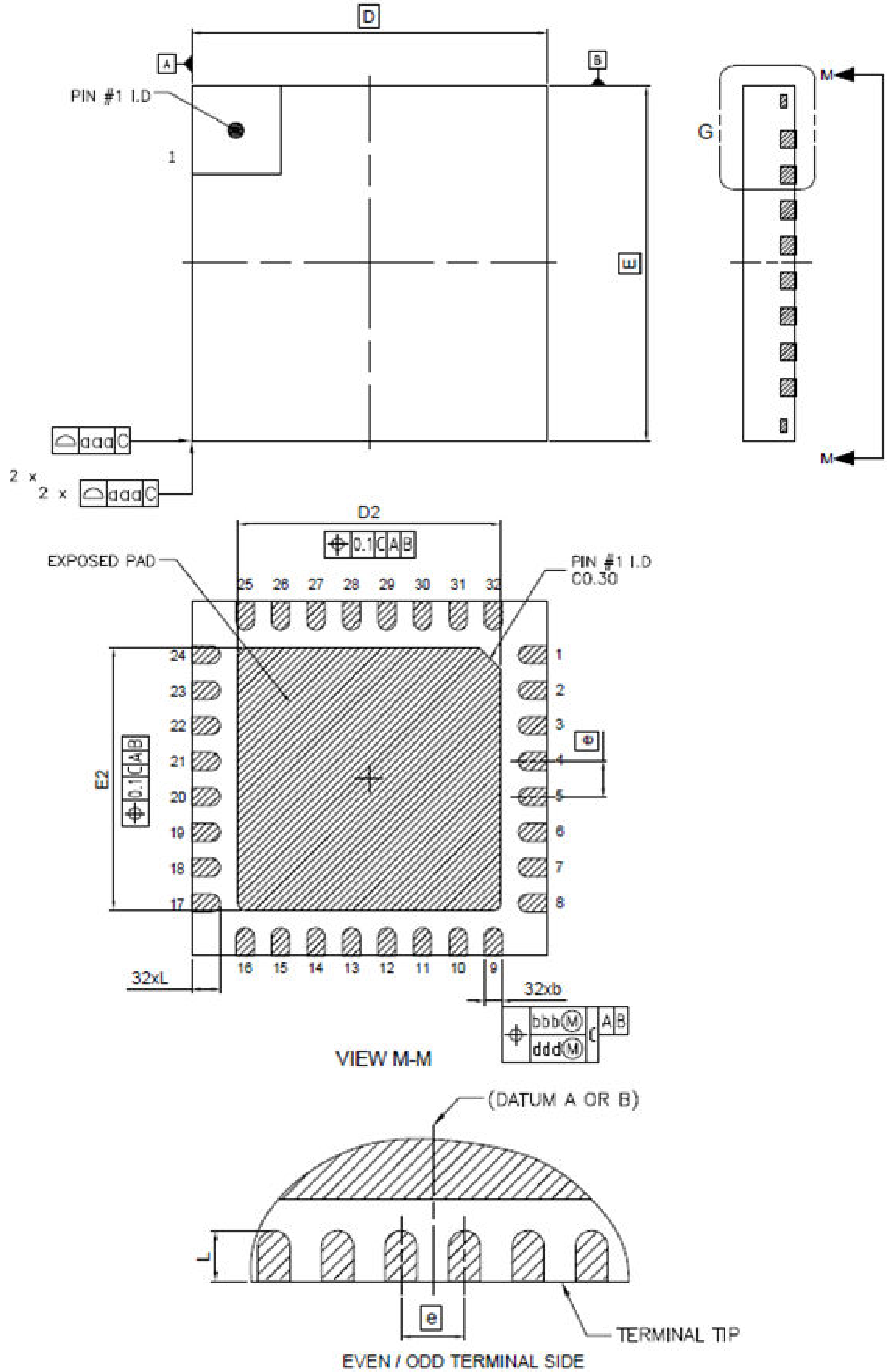
Table 10.1. TQFP48 Package Dimensions

Dimension	Min	Typ	Max
A		7.00 BSC	
A1		3.50 BSC	
B		7.00 BSC	
B1		3.50 BSC	
C	1.00	—	1.20
D	0.17	—	0.27
E	0.95	—	1.05
F	0.17	—	0.23
G		0.50 BSC	
H	0.05	—	0.15
J	0.09	—	0.20
K	0.50	—	0.70
L	0	—	7
M		12 REF	
N	0.09	—	0.16
P		0.25 BSC	
R	0.150	—	0.250
S		9.00 BSC	
S1		4.50 BSC	
V		9.00 BSC	
V1		4.50 BSC	
W		0.20 BSC	
AA		1.00 BSC	

Note:
1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

11. QFN32 Package Specifications

11.1 QFN32 Package Dimensions



12. Revision History

Revision 0.5

February, 2018

- 4.1 Electrical Characteristics updated with latest characterization data and production test limits.
- Added 4.1.3 Thermal Characteristics.
- Added 4.2 Typical Performance Curves section.
- Corrected OPA / VDAC output connections in Figure 5.14 APORT Connection Diagram on page 119.

Revision 0.1

May 1st, 2017

Initial release.